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Defect Detection with Transient Current Testing and its Potential for Deep Sub-micron CMOS ICs

M Sachdev, P Janssen, V Zieren - Proceedings of the 1998 IEEE International Test Conference, 1998 - doi.ieeeecs.org

... equally important to find out which transient current segments are ... device provides the key for fault detection ... only the peak and the quiescent current level of ...

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Transient power supply current testing of digital CMOS circuits

RZ Makki, ST Su, T Nagle - Test Conference, 1995. Proceedings., International, 1995 - ieeexplore.ieee.org

... assume that the normal dynamic (transient) current ... is distinguishably higher than the quiescent current ZDD ... the absence of the iDDT pulse indicates a fault. ...

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Quiescent power supply current measurement for CMOS IC defect detection

CF Hawkins, JM Soden, RR Fritzsche, LK Homing - Industrial Electronics, IEEE Transactions on, 1989 - ieeexplore.ieee.org

... that exists in a CMOS circuit when all logic states have settled and are in a steady state or quiescent mode. Transient power supply current is the ...

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Transient Current Testing of 0.25 μ m CMOS Devices

B Kruseman, P Janssen, V Zieren - Proceedings of the 1999 IEEE International Test Conference, 1999 - doi.ieeecomputersociety.org

... wait till the current has reached the quiescent level for ... to determine the total charge in a transient peak instead ... 18] integrated the I DD current and compare ...

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Built-in current testing of integrated circuits

WP Maly, PJ Nigh - US Patent 5,026,344, 1991 - freepatentonline.com

... 50, 100 and 150 nanoseconds, a large transient current occurs then ... The quiescent value may vary for different IC circuits ... 6 shows current flow with a gate oxide ...

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CURRENT VS. LOGIC TESTING OF GATE OXIDE SHORT, FLOATING GATE AND BRIDGING FAILURES IN CMOS

R Rodriguez-Montanes, JA Segura, VH Champac, J ... - Test Conference, 1991. Proceedings., International, 1991 - ieeexplore.ieee.org

... shown that some failure mechanisms exhibit a transient behaviour, in t ... current is; expressed in PA (in a fault-free circuit this quiescent current is in ...

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W Maly, P Nigh - Computer-Aided Design, 1988. ICCAD-88. Digest of Technical ..., 1988 - ieeexplore.ieee.org
... the boundary between normal and abnormal quiescent currents ... the voltage drop during peak transient currents ... Compare the voltage across the current Sensor of the ...
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Transient power supply current monitoring—A new test method for CMOS VLSI circuits

ST Su, RZ Makki, T Nagle - Journal of Electronic Testing, 1995 - Springer
... Design for current-testability, drain/source opens, floating gates, shorts, transient power supply ... IDD Q (quiescent power supply current) testing has ...
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Quiescent current analysis and experimentation of defective CMOS circuits

JA Segura, VH Champac, R Rodriguez-Montañés, J ... - Journal of Electronic Testing, 1992 - Springer
... in the field using Inductive Fault Analysis [1], [2 ... Limited experimental data on quiescent current meas- ures are ... of the influence of defect characteristics on ...
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Detection and location of faults and defects using digital signal processing

C Thibeault - VLSI Test Symposium, 1995 - doi.ieeecs.org
... be useful for tech- nologies with significant quiescent current, since their ... ples (once per clock period) current when ICs ... when the chips are in transient state ...
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Increased CMOS IC stuck-at fault coverage with reduced I DDQ test sets

RR Fritzeleier, JM Soden, RK Treece, CF Hawkins - Test Conference, 1990. Proceedings., International, 1990 - ieeexplore.ieee.org
... produce elevated quiescent current in one or more logic states. ... logic 0 and 1 (non-transient logic states ... The difference in unstable fault counts between the ...
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Defect Detection Using Power Supply Transient Signal Analysis - umbc.edu [PDF]

A Germida, Z Yan, JF Plusquellic, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - doi.ieeeecomputersociety.org
... on the analysis of a circuit's parametric properties, for example, propagation delay, magnitude of quiescent supply current or transient response [5 ...
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Built-in current sensor for I DDQ test in CMOS

CW Hsue, CJ Lin - Test Conference, 1993. Proceedings., International, 1993 - ieeexplore.ieee.org
... requirement of large current sink for state-transition transient current. ... RR Fritzeleier and LK Homing, "Quiescent power supply current measurement for ...
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Defect-oriented test methodology for complex mixed-signal circuits

FCM Kuijstermans, M Sachdev, AP Thijssen - European Design and Test Conference, 1995. ED&TC 1995, ..., 1995 - ieeexplore.ieee.org
... can be detected by simple DC, Transient and AC ... due to a leakage current, the quiescent current is strongly ... Defect simulation and fault collapsing The defect sim ...
Cited by 21 - Related articles - Web Search - All 9 versions

Electrical Model of the Floating Gate Defect in CMOS IC's: Implications on I~ D~ D~ Q Testing

VH Champac, A Rubio, J Figueras - IEEE TRANSACTIONS ON COMPUTER AIDED DESIGN OF INTEGRATED ..., 1994 - ieeexplore.ieee.org
... chip with transistors possessing floating gate defects. ... characteristics of both the fault-free transistor ... which produces the same equivalent quiescent current. ...

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Transient current testing based on current (charge) integration

I de Paul, R Picos, JL Rossello, M Roca, E Isern, ... - IDDQ Testing, 1998. Proceedings. 1998 IEEE International ... 1998 - [ieeexplore.ieee.org](#)

... **con- sumption not only during the quiescent periods, but ... Since this technique monitors the transient current, the test ... were chosen to induce a current path in ...**

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Experimental analysis of transient current testing based on chargeobservation

J Segura, I De Paul, M Roca, E Isern, CF Hawkins - Electronics Letters, 1999 - [ieeexplore.ieee.org](#)

... **current and changed only the transient part of the ... charge value was beyond the fault**

free charge ... Open circuits caus- ing quiescent current elevation in latch ...

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IDDQ testing of CMOS opens: an experimental study

AD Singh, H Rasheed, WW Weber - Test Conference, 1995. Proceedings., International, 1995 - [ieeexplore.ieee.org](#)

... **a stable state following a switch- ing transient. Any quiescent current drawn from the power rails, beyond the background junction leakage current, indicates a ...**

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A 2-ns detecting time, 2- μ m CMOS built-in current sensingcircuit

TL Shen, JC Daly, JC Lo - Solid-State Circuits, IEEE Journal of, 1993 - [ieeexplore.ieee.org](#)

... **minimum of 2-ns duration of quiescent power supply current (without excessive transient current) is needed for an accurate current testing result ...**

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Current sensing for built-in testing of CMOS circuits

DBI Feltham, PJ Nigh, LR Carley, W Maly - Computer Design: VLSI in Computers and Processors, 1988. ... 1988 - [ieeexplore.ieee.org](#)

... **In such circuits, peak values of transient currents are ... faulty and "fault-free"**

quiescent currents. ... simulations, one can estimate current differences smaller ...

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Key authors: [J Soden](#) - [C Hawkins](#) - [W Maly](#) - [V Champac](#) - [J Figueras](#)



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M Sachdev, P Janssen, V Zieren - Proceedings of the 1998 IEEE International Test Conference, 1998 - doi.ieeecs.org

... Quiescent current testing (I DDQ) is an important ... To prove the fault detection capability of this method ... Because the transient current waveforms may differ in ...

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Quiescent power supply current measurement for CMOS IC defect detection

CF Hawkins, JM Soden, RR Fritzscheier, LK Horning - Industrial Electronics, IEEE Transactions on, 1989 - ieeexplore.ieee.org

... that exists in a CMOS circuit when all logic states have settled and are in a steady state or quiescent mode. Transient power supply current is the ...

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RZ Maki, ST Su, T Nagle - Test Conference, 1995. Proceedings., International, 1995 - ieeexplore.ieee.org

... assume that the normal dynamic (transient) current ... is distinguishably higher than the quiescent current ZDD ... the absence of the iDDT pulse indicates a fault. ...

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... shown that some failure mechanisms exhibit a transient behaviour, in t ... current is; expressed in PA (in a fault-free circuit this quiescent current is in ...

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A Germida, Z Yan, JF Plusquellic, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - doi.ieeecomputersociety.org

... measurement of an IC's supply current when all nodes have stabilized to a quiescent value. ... Defect Detection using Power Supply Transient Signal Analysis ...

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Quiescent current analysis and experimentation of defective CMOS circuits

JA Segura, VH Champac, R Rodríguez-Montañés, J ... - Journal of Electronic Testing, 1992 - Springer
... in the field using Inductive Fault Analysis [1], [2 ... circuits representative of the defects investigated ... Limited experimental data on quiescent current meas- ures ...
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Transient power supply current monitoring—A new test method for CMOS VLSI circuits

ST Su, RZ Makki, T Nagle - Journal of Electronic Testing, 1995 - Springer
... denotes the peak value of the quiescent supply current ... directly com- puted from the transient portion of ... GOOD CKT FAULT CKT Current Response Current Response ...
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Detection and location of faults and defects using digital signal processing

C Thibeault - VLSI Test Symposium, 1995 - doi.ieeeecs.org
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W Maly, P Nigh - Computer-Aided Design, 1988, ICCAD-88, Digest of Technical ..., 1988 - ieeeexplore.ieee.org
... defines the boundary between normal and abnormal quiescent currents ... the voltage drop during peak transient currents ... in which full adders and current sensors were ...
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IDDQ testing: A review

JM Soden, CF Hawkins, RK Gulati, W Mao - Journal of Electronic Testing, 1992 - Springer
... Abstract. Quiescent power supply current (IDDQ) testing of CMOS ... quality improvement through increased defect and fault detection is described. ...
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Built-in current sensor for I DDQ test in CMOS

CW Hsue, CJ Lin - Test Conference, 1993. Proceedings., International, 1993 - ieeeexplore.ieee.org
... requirement of large current sink for state-transition transient current. ... RR Fritzemeier and LK Homing, "Quiescent power supply current measurement for ...
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A 2-ns detecting time, 2- μ m CMOS built-in current sensing circuit

TL Shen, JC Daly, JC Lo - Solid-State Circuits, IEEE Journal of, 1993 - ieeeexplore.ieee.org
... of 2-ns duration of quiescent power supply current (without excessive transient current) is needed ... and P. Nigh, "Built-in current testing—Feasibility ...
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IDDQ testing of CMOS opens: an experimental study

AD Singh, H Rasheed, WW Weber - Test Conference, 1995. Proceedings., International, 1995 - ieeeexplore.ieee.org
... a stable state following a switch- ing transient. Any quiescent current drawn from the power rails, beyond the background junction leakage current, indicates a ...
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Current sensing for built-in testing of CMOS circuits

DBI Feltham, PJ Nigh, LR Carley, W Maly - Computer Design: VLSI in Computers and Processors, 1988. ... , 1988 - ieeeexplore.ieee.org
... In such circuits, peak values of transient currents are ... faulty and "fault-free" quiescent currents. ... simulations, one can estimate current differences smaller ...
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Enhancement of resolution in supply current based testing for large ICs

YK Malaiya, AP Jayasumana, Q Tong, SM Menon - Proc. IEEE VLSI Test Symp, 1991 - doi.ieeecomputersociety.org

... such as NMOS and TTL, the quiescent current can be ... between states, and the noise in transient current to provide ... the testing of an IC by current measurements. ...

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Electrical Model of the Floating Gate Defect in CMOS IC's: Implications on I~ D~ D~ Q Testing

VH Champac, A Rubio, J Figueras - IEEE TRANSACTIONS ON COMPUTER AIDED DESIGN OF INTEGRATED ... 1994 - ieeeexplore.ieee.org

... chip with transistors possessing floating gate defects. ... characteristics of both the fault-free transistor ... which produces the same equivalent quiescent current. ...

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Increased CMOS IC stuck-at fault coverage with reduced I DDQ test sets

RR Fritzscheier, JM Soden, RK Treece, CF Hawkins - Test Conference, 1990. Proceedings., International, 1990 - ieeeexplore.ieee.org

... produce elevated quiescent current in one or more logic states. ... logic 0 and 1 (non-transient logic states ... The difference in untestable fault counts between the ...

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Built-in current testing of integrated circuits

WP Maly, PJ Nigh - US Patent 5,025,344, 1991 - freepatentsonline.com

... including radiation induced latch-up or other transient faults. ... may result in still higher quiescent current flows which ... pads are use while current sensors are ...

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Experimental analysis of transient current testing based on chargeobservation

J Segura, I De Paul, M Roca, E Isem, CF Hawkins - Electronics Letters, 1999 - ieeeexplore.ieee.org

... current and changed only the transient part of ... Open circuits caus- ing quiescent current elevation in latch ... with this technique; it drew less current than the ...

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Quiescent power supply current measurement for CMOS IC defect detection

CF Hawkins, JM Soden, RR Fritzsche, LK Horning - Industrial Electronics, IEEE Transactions on, 1989 - [ieeexplore.ieee.org](#)

... quite useful for detecting stuck-at faults themselves using a ... The peak of the transient current is approximately 60 ... in about 100 ns to a low quiescent current. ...

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Transient Current Testing of 0.25 μ m CMOS Devices

B Kruseman, P Janssen, V Zieren - Proceedings of the 1999 IEEE International Test Conference, 1999 - [doi.ieeeecomputersociety.org](#)

... wait till the current has reached the quiescent level for ... to determine the total charge in a transient peak instead ... 18] integrated the I DD current and compare ...

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Detection and location of faults and defects using digital signal processing

C Thibault - VLSI Test Symposium, 1995 - [doi.ieeecs.org](#)

... when the chips are in transient state ... technologies with significant sup- ply quiescent current, since DC ... cir- cuits based on supply current," in International ...

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IDDQ testing: A review

JM Soden, CF Hawkins, RK Gulati, W Mao - Journal of Electronic Testing, 1992 - Springer

... It may seem costly to reject ICs that have in- creased quiescent power supply current but are still per- forming their logic functions ... 4. Fault Detection ...

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Test challenges for deep sub-micron technologies - [►acm.org](#) [PDF]

KT Cheng, S Dey, M Rodgers, K Roy - Design Automation Conference, 2000. Proceedings 2000. 37th, 2000 - [ieeexplore.ieee.org](#)

... reduction techniques for the application of current testing ... of circuit and more complex fault types (eg ... DFT and test solutions and CAD environment ahead of time. ...

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DELAY TESTING OF DIGITAL CIRCUITS BY OUTPUT WAVEFORM ANALYSIS

P Franco, EJ McCluskey - Test Conference, 1991. Proceedings., International, 1991 - [ieeexplore.ieee.org](#)

... and fault-free waveforms before the sampling time, and compared ... required in the past, catastrophic fault models have ... These defects are modeled by delay faults. ...

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Defect Detection Using Power Supply Transient Signal Analysis - [►umbc.edu](#) [PDF]

A Gernida, Z Yan, JF Plusquellic, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - [doi.ieeeecomputersociety.org](#)

... nodes have stabilized to a quiescent value. ... Defect Detection using Power Supply Transient Signal Analysis ... Several dynamic supply current I DD -based approaches ...

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Built-in current testing of integrated circuits

W/P Maly, P.J Nigh - US Patent 5,025,344, 1991 - [freepatentsonline.com](#)
... including radiation induced latch-up or other transient faults. ... may result in still higher quiescent current flows which ... pads are use while current sensors are ...

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Enhancement of resolution in supply current based testing for large ICs

YK Malaiya, AP Jayasumana, Q Tong, SM Menon - Proc. IEEE VLSI Test Symp, 1991 - [doi.ieeecomputersociety.org](#)

... The width of transient current pulse, loading of VDD pin due to output buffers and ... Let us assume that the additional quiescent supply current, if, is ...

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Transient current testing based on current (charge) integration

I de Paul, R Picos, JL Rossello, M Roca, E Isern, ... - IDDQ Testing, 1998. Proceedings. 1998 IEEE International ... 1998 - [ieeexplore.ieee.org](#)

... consumption not only during the quiescent periods, but ... be achieved by measuring the transient current at the ... activity difference between the fault free and ...

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Current sensing for built-in testing of CMOS circuits

DBI Feltham, PJ Nigh, LR Carlsy, W Maly - Computer Design: VLSI in Computers and Processors, 1988. ... 1988 - [ieeexplore.ieee.org](#)

... a forward-biased diode, and appears only during transient current peaks as ... and CF Hawkins, "Measurements of Quiescent Power Supply Current for CMOS ...

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Experimental analysis of transient current testing based on charge observation

J Segura, I De Paul, M Roca, E Isern, CF Hawkins - Electronics Letters, 1999 - [ieeexplore.ieee.org](#)

... current and changed only the transient part of ... Open circuits causing quiescent current elevation in latch ... with this technique; it drew less current than the ...

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Defect-oriented test methodology for complex mixed-signal circuits

FCM Kuijstermans, M Sachdev, AP Thijssen - European Design and Test Conference, 1995. ED&TC 1995. ... 1995 - [ieeexplore.ieee.org](#)

... In a Class AB amplifier can be detected by simple DC, Transient and AC ... in the analog domain, the output of a fault-free circuit ... Its quiescent current is zero ...

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Comparison of defect detection capabilities of current-based and voltage-based test methods

- [►lirmm.fr pdf](#)

B Kruseman - European Test Workshop, 2000. Proceedings. IEEE, 2000 - [ieeexplore.ieee.org](#)

... over a decade ago when quiescent current testing ... Dynamic current-based tests or transient current testing (IDDT ... For example delay fault testing requires more ...

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Current-Based Testing for Deep-Submicron VLSIs - [►uwaterloo.ca pdf](#)

M Sachdev - IEEE DESIGN & TEST OF COMPUTERS, 2001 - [doi.ieeecs.org](#)

... VLSI with very high (>100 mA) quiescent current, the application ... to identify a smooth, monotonic transient-current waveform ... of a deep-micron current-based test ...

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I DDQ testing and defect classes-a tutorial

JM Soden, CF Hawkins - Custom Integrated Circuits Conference, 1995., Proceedings of ..., 1995 - [ieeexplore.ieee.org](#)

... Physical shorts and their related fault models bring to mind an ... ma; seem costly to reject ICs that have increased quiescent power supply current but are ...

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... of Defective CMOS Devices Using Correlation and Regression Analysis of Frequency Domain Transient ... - [►umbc.edu \(PDF\)](#)

J Plusquellic, D Chiarulli, S Levitan - INTERNATIONAL TEST CONFERENCE, 1997 - [doi.ieeecs.org](#)

... all nodes have stabilized to a quiescent value [12 ... Several dynamic supply current (I DD -based) approaches ... frequency components of the transient signals combine ...

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CMOS Open Defect Detection by Supply Current Test - [►uci.edu \(PDF\)](#)

M Hashizume, M Ichimiya, H Yotsuyanagi, T Tamesada - Proc. Design, Automation and Test in Europe, 2001 - [doi.ieeecomputersociety.org](#)

... circuit and is sensitized, large quiescent supply current ... analysis of frequency domain transient signal data ... of Logic Circuits Based on Supply Current Using Auto ...

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Experimental Results on BIC Sensors for Transient Current Testing

R Picos, M Roca, E Isern, J Segura, E Garcia- ... - Journal of Electronic Testing, 2000 - Springer

... the activation of the faults by enabling or ... In sensor based on transient current integration (charge) show ... defects raising the quiescent current consumption (I ...

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Built-in current sensor for/spl Delta//sub DDQ/testing - [►upc.es \(PDF\)](#)

JR Vazquez, J Pineda de Gyvez - Solid-State Circuits, IEEE Journal of, 2004 - [ieeexplore.ieee.org](#)

... 2 by the current source and the capacitance) is in the quiescent state, then ... operating mode, the switch is closed and in each transient, a voltage ...

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